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April 1<sup>st</sup>, 2010 Renesas Electronics Corporation

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 $4 \text{ M SRAM} (256\text{-kword} \times 16\text{-bit})$ 



ADE-203-1072A (Z) Rev. 1.0 Jun. 10, 1999

#### **Description**

The Hitachi HM62W16258BI Series is 4-Mbit static RAM organized 262,144-word × 16-bit. HM62W16258BI Series has realized higher density, higher performance and low power consumption by employing Hi-CMOS process technology. It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in standard 44-pin plastic TSOPII.

#### **Features**

• Single 3.3 V supply:  $3.3 \text{ V} \pm 0.3 \text{ V}$ 

• Fast access time: 70 ns (max)

Power dissipation:

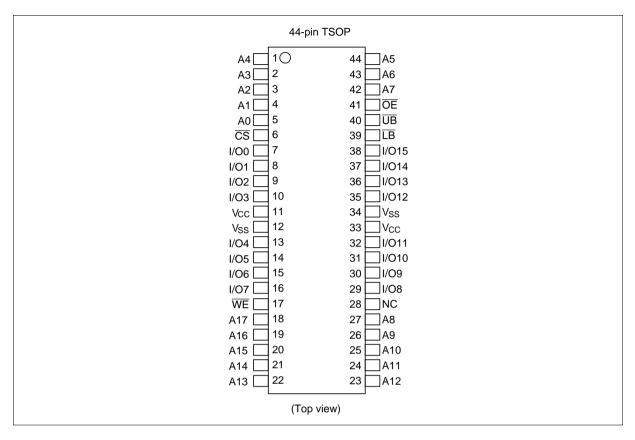
— Active: 9.9 mW (typ)— Standby: 3.3 μW (typ)

- Completely static memory.
  - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output.
  - Three state output
- Battery backup operation.
- Temperature range: -40 to 85°C

### **Ordering Information**

Type No.	Access time	Package
HM62W16258BLTTI-7	70 ns	400-mil 44-pin plastic TSOPII (normal-bend type) (TTP-44DB)

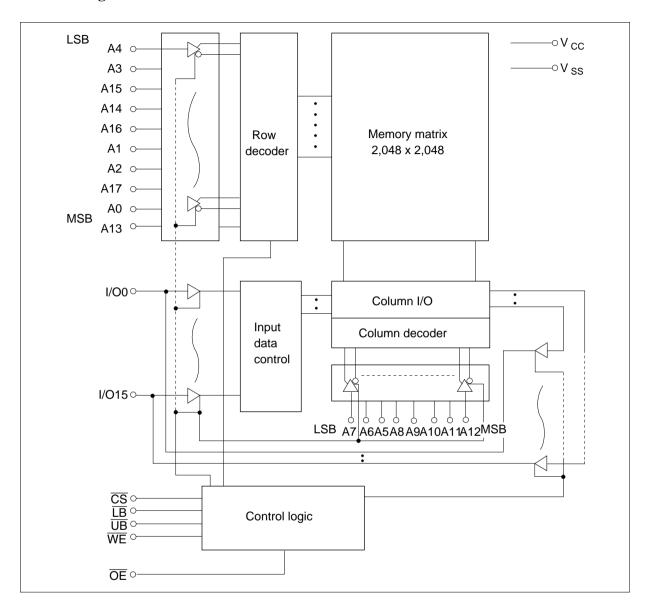
### **Pin Arrangement**



# **Pin Description**

Pin name	Function
A0 to A17	Address input
I/O0 to I/O15	Data input/output
CS	Chip select
WE	Write enable
ŌĒ	Output enable
LB	Lower byte select
ŪB	Upper byte select
V <sub>cc</sub>	Power supply
V <sub>SS</sub>	Ground
NC	No connection

# **Block Diagram**



# **Operation Table**

CS	WE	OE	<del>UB</del>	LB	I/O0 to I/O7	I/O8 to I/O15	Operation
Н	×	×	×	×	High-Z	High-Z	Standby
×	×	×	Н	Н	High-Z	High-Z	Standby
L	Н	L	L	L	Dout	Dout	Read
L	Н	L	Н	L	Dout	High-Z	Lower byte read
L	Н	L	L	Н	High-Z	Dout	Upper byte read
L	L	×	L	L	Din	Din	write
L	L	×	Н	L	Din	High-Z	Lower byte write
L	L	×	L	Н	High-Z	Din	Upper byte write
L	Н	Н	×	×	High-Z	High-Z	Output disable

Note: H:  $V_{IH}$ , L:  $V_{IL}$ ,  $\times$ :  $V_{IH}$  or  $V_{IL}$ 

# **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage relative to V <sub>SS</sub>	V <sub>cc</sub>	-0.5 to + 4.6	V
Terminal voltage on any pin relative to V <sub>ss</sub>	V <sub>T</sub>	$-0.5^{*1}$ to $V_{CC} + 0.3^{*2}$	V
Power dissipation	P <sub>T</sub>	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  min: -3.0 V for pulse half-width  $\leq 30$  ns.

2. Maximum voltage is +4.6 V.

# **DC Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	V <sub>cc</sub> 3.0 3.3		3.6	V		
	V <sub>ss</sub>	0	0	0	V	
Input high voltage	V <sub>IH</sub>	2.2	_	V <sub>cc</sub> + 0.3	V	
Input low voltage	$V_{\text{IL}}$	-0.3	_	0.6	V	1
Ambient temperature range	Та	-40	_	85	°C	

Note: 1.  $V_{IL}$  min: -3.0 V for pulse half-width  $\leq 30$  ns.

### **DC** Characteristics

Operating current $I_{cc}$ — 20 mA $\overline{CS} = V_{IL}$ , $V_{I/O} = V_{SS}$ to $V_{cc}$ Average HM62W16258BI-7 $I_{cc1}$ — 70 mA Min. cycle, duty = 100%, operating current $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , Others $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , others $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , others $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , others $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , others $I_{I/O} = 0$ mA, $\overline{CS} = V_{IL}$ , others $I_{I/O} = 0$ mA, $I_{I/O} = 0$ mA	Parameter	Symbol	Symbol Min		Max	Unit	Test conditions		
$\overline{LB} = \overline{UB} = V_{\text{IH}}, \ V_{\text{I/O}} = V_{\text{SS}} \text{ to } V_{\text{CC}}$ $\overline{CS} = V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}, \ I_{\text{I/O}} = 0$ $\overline{CS} = V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}, \ I_{\text{I/O}} = 0$ $\overline{CS} = V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}, \ I_{\text{I/O}} = 0$ $\overline{CS} = V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}$ $\overline{CS} = V_{\text{IL}}, \ Others = V_{\text{IH}}/V_{\text{IL}}$ $\overline{CS} = V_{\text{IH}}$	Input leakage current	I <sub>LI</sub>	_	_	1	μΑ	Vin = V <sub>SS</sub> to V <sub>CC</sub>		
Average operating current $I_{CC2} = \begin{bmatrix} I_{CC1} & -I_{CC1} & -I_{CC1} & -I_{CC1} & -I_{CC2} & -I_{C$	Output leakage current	I <sub>LO</sub>	_	_	1	μА	$\overline{\overline{CS}} = \overline{V_{IH}} \text{ or } \overline{\overline{OE}} = V_{IH} \text{ or } \overline{\overline{WE}} = V_{IL}, \text{ or } \overline{\overline{LB}} = \overline{\overline{UB}} = V_{IH}, V_{I/O} = V_{SS} \text{ to } V_{CC}$		
operating current $ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Operating current	I <sub>cc</sub>	_	_	20	mA	$\overline{\text{CS}} = \text{V}_{\text{IL}}, \text{ Others} = \text{V}_{\text{IH}}/\text{V}_{\text{IL}}, \text{ I}_{\text{I/O}} = 0 \text{ mA}$		
$\begin{split} I_{\text{I/O}} &= 0 \text{ mA, } \overline{\text{CS}} \leq 0.2 \text{ V,} \\ V_{\text{IH}} \geq V_{\text{CC}} - 0.2 \text{ V, } V_{\text{IL}} \leq 0.2 \text{ V} \end{split}$ Standby current $I_{\text{SB}} & - & - & 0.3 \text{ mA}  \overline{\text{CS}} = V_{\text{IH}} \\ \text{Standby current} & I_{\text{SB1}} & - & 1 & 40 & \mu\text{A}  \frac{0 \text{ V} \leq \text{Vin}}{\overline{\text{CS}}} \geq V_{\text{CC}} - 0.2 \text{ V} \end{split}$	operating	BI-7 I <sub>cc1</sub>	_	_	70	mA	$I_{I/O} = 0 \text{ mA}, \overline{CS} = V_{IL},$		
Standby current $I_{SB1}$ — 1 40 $\mu A$ $0 \text{ V} \leq \text{Vin}$ $\overline{\text{CS}} \geq \text{V}_{CC} - 0.2 \text{ V}$		I <sub>CC2</sub>	_	3	15	mA			
$\overline{\text{CS}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V}$	Standby current	I <sub>SB</sub>	_	_	0.3	mA	<del>CS</del> = V <sub>IH</sub>		
Output high voltage $V_{OH}$ 2.4 — $V_{OH}$ $I_{OH}$ = -1 mA	Standby current	I <sub>SB1</sub>	_	1	40	μΑ	-		
	Output high voltage	$V_{OH}$	2.4	_	_	V	$I_{OH} = -1 \text{ mA}$		
$V_{\infty} - 0.2$ — $V$ $I_{OH} = -100 \mu\text{A}$			$V_{\infty} - 0$	).2 —	_	V	$I_{OH} = -100 \mu A$		
Output low voltage $V_{OL}$ — $0.4$ $V$ $I_{OL}$ = 2 mA	Output low voltage	V <sub>OL</sub>	_	_	0.4	V	I <sub>OL</sub> = 2 mA		
$-$ 0.2 V $I_{OL} = 100  \mu A$			_	_	0.2	V	$I_{OL} = 100  \mu A$		

Notes: 1. Typical values are at  $V_{\rm CC}$  = 3.0 V, Ta = +25°C and not guaranteed.

# **Capacitance** (Ta = +25°C, f = 1.0 MHz)

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin	_	_	8	pF	Vin = 0 V	1
Input/output capacitance	C <sub>I/O</sub>	_	_	10	pF	$V_{I/O} = 0 V$	1

Note: 1. This parameter is sampled and not 100% tested.

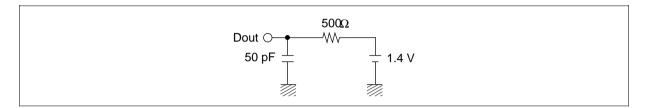
AC Characteristics (Ta = -40 to +85°C,  $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$ , unless otherwise noted.)

#### **Test Conditions**

• Input pulse levels:  $V_{IL} = 0.4 \text{ V}$ ,  $V_{IH} = 2.4 \text{ V}$ 

• Input rise and fall time: 5 ns

Input timing reference levels: 1.4 V
Output timing reference levels: 1.4 V
Output load (Including scope and jig)



HM62W16258BI

#### **Read Cycle**

		_			
		-7			
Parameter	Symbol	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	70	_	ns	
Address access time	t <sub>AA</sub>	_	70	ns	
Chip select access time	t <sub>ACS</sub>	_	70	ns	
Output enable to output valid	t <sub>OE</sub>	_	40	ns	
Output hold from address change	t <sub>oh</sub>	10	_	ns	
TB, UB access time	t <sub>BA</sub>	_	70	ns	
Chip select to output in low-Z	t <sub>CLZ</sub>	10	_	ns	2, 3
LB, UB enable to low-z	t <sub>BLZ</sub>	5	_	ns	2, 3
Output enable to output in low-Z	t <sub>OLZ</sub>	5	_	ns	2, 3
Chip deselect to output in high-Z	t <sub>CHZ</sub>	0	25	ns	1, 2, 3
LB, UB disable to high-Z	t <sub>BHZ</sub>	0	25	ns	1, 2, 3
Output disable to output in high-Z	t <sub>OHZ</sub>	0	25	ns	1, 2, 3

ns

ns

ns

ns

ns

2

1, 2

1, 2

HM62W16258BI

30

0

5

0

0

25

25

#### Write Cycle

Data to write time overlap

Data hold from write time

Write to output in high-Z

Output active from end of write

Output disable to output in High-Z

		-7			
Parameter	Symbol	Min	Max	Unit	Notes
Write cycle time	t <sub>wc</sub>	70	_	ns	
Address valid to end of write	t <sub>AW</sub>	60	_	ns	
Chip selection to end of write	t <sub>cw</sub>	60	_	ns	5
Write pulse width	t <sub>wP</sub>	50	_	ns	4
LB, UB valid to end of write	t <sub>BW</sub>	55	_	ns	
Address setup time	t <sub>AS</sub>	0	_	ns	6
Write recovery time	t <sub>wR</sub>	0	_	ns	7

 $t_{DW}$ 

 $t_{DH}$ 

 $t_{ow}$ 

 $t_{OHZ}$ 

 $t_{WHZ}$ 

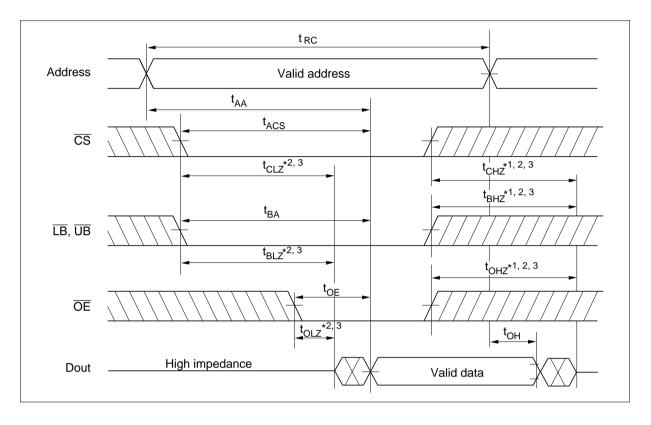
Notes: 1.  $t_{CHZ}$ ,  $t_{CHZ}$ ,  $t_{WHZ}$  and  $t_{BHZ}$  are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for a given device and from device to device.
- 4. A write occures during the overlap of a low  $\overline{CS}$ , a low  $\overline{WE}$  and a low  $\overline{LB}$  or a low  $\overline{UB}$ . A write begins at the latest transition among  $\overline{CS}$  going low,  $\overline{WE}$  going low and  $\overline{LB}$  going low or  $\overline{UB}$  going low. A write ends at the earliest transition among  $\overline{CS}$  going high,  $\overline{WE}$  going high and  $\overline{LB}$  going high or  $\overline{UB}$  going high.  $t_{WP}$  is measured from the beginning of write to the end of write.
- 5.  $t_{cw}$  is measured from the later of  $\overline{CS}$  going low to the end of write.
- 6.  $t_{AS}$  is measured from the address valid to the beginning of write.
- 7.  $t_{WR}$  is measured from the earliest of  $\overline{CS}$  or  $\overline{WE}$  going high to the end of write cycle.

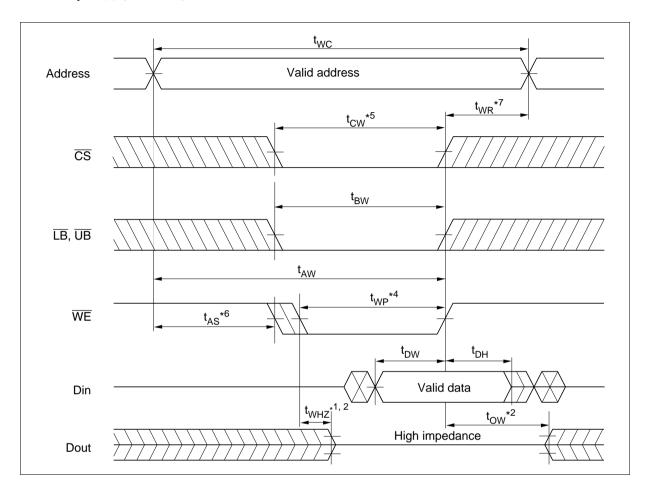
7

# **Timing Waveform**

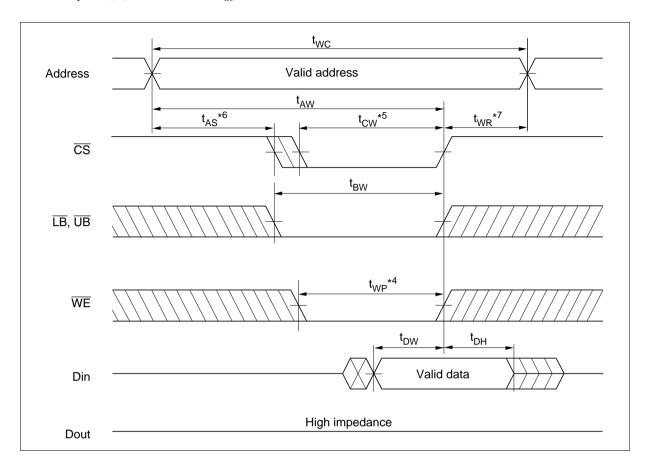
# Read Cycle



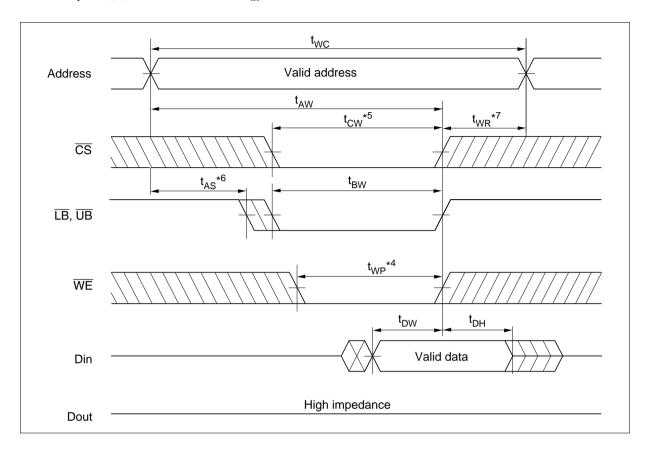
# Write Cycle (1) (WE Clock)



Write Cycle (2) ( $\overline{\text{CS}}$  Clock,  $\overline{\text{OE}} = V_{\text{IH}}$ )



Write Cycle (3) ( $\overline{LB}$ ,  $\overline{UB}$  Clock,  $\overline{OE} = V_{IH}$ )



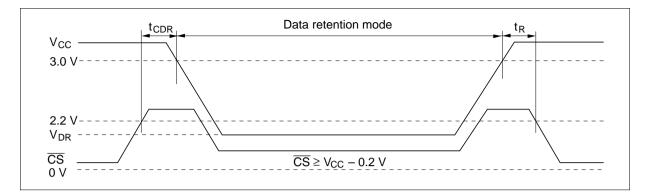
# **Low V**<sub>CC</sub> **Data Retention Characteristics** ( $Ta = -40 \text{ to } +85^{\circ}\text{C}$ )

Parameter	Symbol	Min	Typ* <sup>3</sup>	<sup>3</sup> Max	Unit	Test conditions <sup>*2</sup>
V <sub>cc</sub> for data retention	$V_{DR}$	2.0	_	_	V	$\begin{array}{c} \text{Vin} \geq 0\text{V} \\ \text{(1)} \ \overline{CS} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or} \\ \text{(2)} \ \overline{LB} = \overline{UB} \geq \text{V}_{\text{CC}} - 0.2 \text{ V} \\ \overline{CS} \leq 0.2 \text{ V} \end{array}$
Data retention current	I <sub>CCDR</sub> *1	_	0.8	20	μΑ	$\begin{array}{c} V_{\text{CC}} = 3.0 \text{ V}, \text{ Vin} \ge 0\text{V} \\ \text{(1)} \   \overline{\text{CS}} \ge V_{\text{CC}} - 0.2 \text{ V or} \\ \text{(2)} \   \overline{\text{LB}} = \overline{\text{UB}} \ge V_{\text{CC}} - 0.2 \text{ V} \\ \overline{\text{CS}} \le 0.2 \text{ V} \end{array}$
Chip deselect to data retention time	t <sub>CDR</sub>	0	_	_	ns	See retention waveform
Operation recovery time	t <sub>R</sub>	t <sub>RC</sub> *4	_	_	ns	_

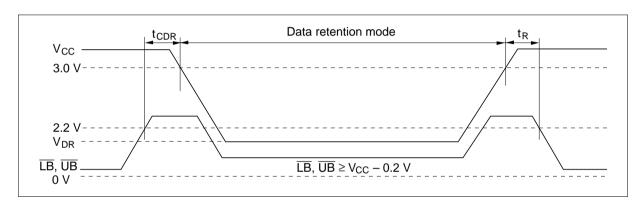
Notes: 1. 10  $\mu$ A max. at Ta = 0 to +40°C.

- 2.  $\overline{CS}$  controls address buffer,  $\overline{WE}$  buffer,  $\overline{OE}$  buffer,  $\overline{LB}$ ,  $\overline{UB}$  buffer and Din buffer. If  $\overline{CS}$  controls data retention mode, Vin levels (address,  $\overline{WE}$ ,  $\overline{OE}$ ,  $\overline{LB}$ ,  $\overline{UB}$ ,  $\overline{UB}$ ,  $\overline{UB}$ ) can be in the high impedance state. If  $\overline{LB}$ ,  $\overline{UB}$  controls data retention mode,  $\overline{LB}$ ,  $\overline{UB}$  must be  $\overline{LB} = \overline{UB} \ge V_{cc} 0.2 \text{ V}$ ,  $\overline{CS}$  must be  $\overline{CS} \le 0.2 \text{ V}$ . The other input levels (address,  $\overline{WE}$ ,  $\overline{OE}$ ,  $\overline{I/O}$ ) can be in the high impedance state.
- 3. Typical values are at  $V_{\rm CC}$  = 3.0 V, Ta = +25 °C and not guaranteed.
- 4.  $t_{RC}$  = read cycle time.

# Low V<sub>CC</sub> Data Retention Timing Waveform (1) ( $\overline{CS}$ Controlled)

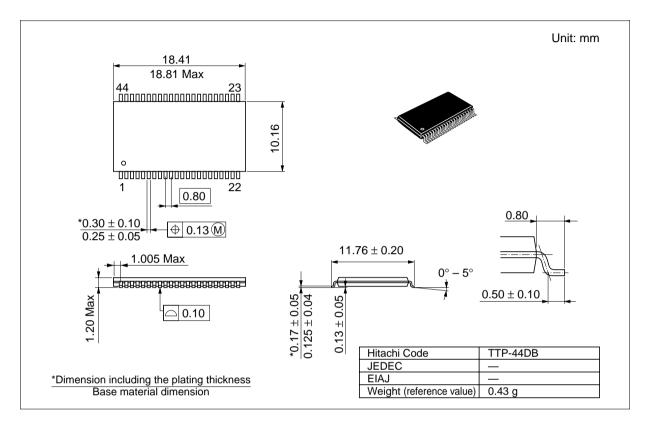


# Low $V_{CC}$ Data Retention Timing Waveform (2) $(\overline{LB}, \overline{UB} \ Controlled)$



# **Package Dimensions**

#### HM62W16258BLTTI Series (TTP-44DB)



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